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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/688,516	CHANG ET AL.	
Examiner	Art Unit	
Minh Nguyen	2816	

	SEARCHED		
Class	Subclass	Date	Examiner
331	16	6/10/2005	MN
above	updated	8/27/2005	MN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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Interference prin	search, see tout	8/27/2005	MN

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (USPUB, USPAT, JPO, EPO, DERWENT, IBM_TDB), see printout	6/10/2005	MN
Limited search (331/1A, 1R, 16-18, 25, 34, 177R, 117D, 175-176, 185, 186; 327/538,539), see printout	6/10/2005	MN
Updated	8/27/2005	MN